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BriefSummary (ext= 35) X ((5))

It has now been found that a relatively simple and effective process is provided for chemically bonding a thermoset resin to a poly-p-xylylene substrate by exposing the poly-p-xylylene to a cold plasma in a confined region for a period of time sufficient to chemically modify the surface of the poly-p-xylylene exposed to the cold plasma, depositing an uncured liquid thermosetting resin over the chemically modified poly-p-xylylene surface; and then heating the thermosetting resin and poly-p-xylylene at a temperature and time sufficient to both cure the thermosetting resin into a solid thermoset resin and chemically bond the chemically modified surface of the poly-p-xylylene to the thermoset resin in situ.

Detailed Description Text - DETX (2):

The basic process of the present invention may be more explicitly defined as a process for chemically bonding a <u>thermoset</u> resin to a poly-p-xylylene substrate comprising; providing a cold plasma within a confined region evacuated to a pressure lower than about 100 torr; exposing at least one <u>surface</u> of the poly-p-xylylene substrate directly to said plasma within said region for a period of time sufficient to incorporate oxygen-containing functional groups thereinto which contain active hydrogen atoms; depositing an uncured liquid <u>thermosetting</u> resin capable of chemically reacting with active hydrogen atoms over the plasma treated poly-p-xylylene <u>surface</u>; and heating the <u>thermosetting</u> resin and poly-p-xylylene at a temperature at which the thermosetting resin

[0014] The present invention provides a method for manufacturing a semiconductor package including the steps of: forming at least one curable resin layer: forming and receiving therein a semiconductor chip; placing the package substrate on the curable resin layer, with the top opening being closed by the curable resin layer; and curing the curable resin layer to form a cap member encapsulating the semiconductor chip in the cavity.

[0047] Thereafter, the curable resin layer 15a is heated from the bottom of the

[0047] Thereafter, the curable resin layer 15a is heated from the bottom of the mold die 22 for two to three hours at a temperature of 200 degrees C. or below, preferably between 120 and 150 degrees C., for a thermosetting process. This provides the encapsulation structure shown in FIG. 10, without using an adhesive, wherein the curable resin layer 15a adhered onto the wall <u>substrate</u> 12 during the <u>curing</u> process absorbs a pressure rise due to the expansion of the air inside the cavity 13.

[0048] The curable resin layer 15a has a concave inner surface at each opening due to the pressure applied at the initial stage of the heating at which the curable resin layer 15a has a lower viscosity. In the encapsulation structure shown in FIG. 10, the top of the cured resin 15 adheres at the bottom of the wall <u>substrate</u> 12 during the <u>curing</u> step, whereby the cured resin 15 constitutes the cap member for each cavity 13. The bottom of the cured resin

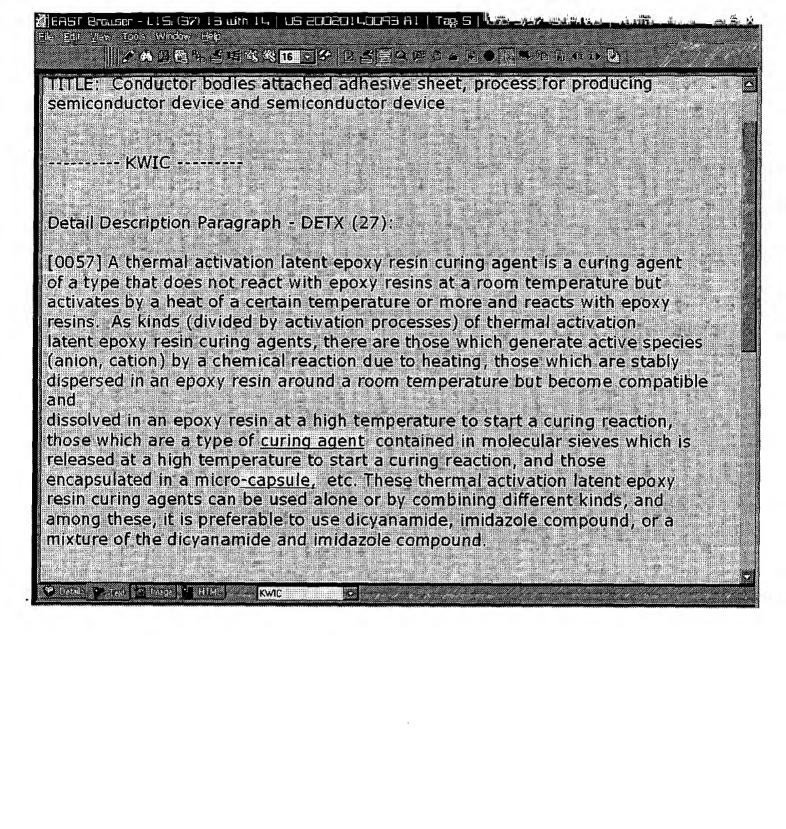
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KWIC [0133] The composition of the present invention can also contain other various additives as far as the object of the present invention is not impaired. These
additives as far as the object of the present invention is not impaired. These
other additives include a reinforcing material such as glass fibers, carbon fibers, asbestos fibers, rock wool, calcium carbonate, quartz sand, bentonite, clay, wollastonite, barium sulfate, glass beads, mica and titanium oxide, filler, antioxidant (phosphorus based, sulfur based, etc.), ultraviolet absorbent, thermal stabilizer (hindered phenol based, etc.), lubricant, releasing agent, antistatic agent, anti-blocking agent, colorant including dye and pigment, flame retarder (halogen based, phosphorus based, etc.), flame retarding aid (antimony compound such as antimony trioxide, zirconium oxide, molybdenum oxide, etc.), foaming agent, crosslinking agent (e.g., polyepoxy compound, isocyanate compound, acid anhydride, etc.), etc. Furthermore, any other synthetic resin (e.g., polyamide resin, polystyrene resin, acrylic resin, polyethylene resin, ethylene/vinyl acetate copolymer, phenoxy resin, epoxy resin, silicone resin, etc.) can also be contained.
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	<u>epoxy</u> resin composition can further contain appropria nti <u>-foaming</u> agents, silane coupling agents, pigments, a arbon black.	
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The finality of the of mailed ____ is withdrawn in view of the new grounds of agreedion below.



#EAST Brouger - L28. (19) 3 and 27 | US ZOCZOCZZZO: A: | 150; 4 | 455; 7. eik edik Mew Igo's Window Help PGPUB-DOCUMENT-NUMBER: 20020022681 DOCUMENT-IDENTIFIER: US 20020022681 A1 TITLE: Epoxy resin composition ------ KWIC ------BSTX: [0005] It is well known to add surfactants to epoxy resin compositions in order to reduce voids. Known surfactants are fluorochemical surfactants such as Florade FC-170C, FC-430 and FC-431 from 3M-Sumitomo Co., Ltd. and silicone surfactants such as KF351, KF945 and KF618 from Shin-Etsu Chemical Co., Ltd. However, where silicone plasticizers are added to epoxy resin compositions, surfactants commonly used as anti-foaming agents are not effective for inhibiting the formation of bubbles. It is impossible to completely remove voids in such silicone component-containing compositions. A study has not been made on the anti-foaming problem associated with the sealing methods including potting, COB and screen printing. It is merely attempted to reduce the viscosity or thixotropy of the resin in order to improve infiltration.

